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Supporting Information

Plasma Induced Transformation: A New Strategy to in situ Engineer

MOF-derived Heterointerface for High-Efficiency Electrochemical

Hydrogen Evolution

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Fig. S1. XRD pattern of ZIF-67/CC.



Fig. S2. (a) XRD patterns of CC and $Co_4N-Co_3O_4-C/CC$, and (b) Raman spectra of ZIF-67/CC and $Co_4N-Co_3O_4-C/CC$.



Fig. S3. SEM images of (a)-(c) Co₄N-Co₃O₄-C/CC-1, (d) and (e) Co₄N-Co₃O₄-C/CC-10.



Fig. S4. High-resolution XPS spectra of (a) Co 2p and (b) N 1s of Co₄N-C/CC.



Fig. S5. High-resolution XPS spectra of (a) Co 2p and (b) O 1s of Co₃O₄-C/CC.



Fig. S6. EDX results of (a) $Co_4N-Co_3O_4$ -C/CC-1 and (b) $Co_4N-Co_3O_4$ -C/CC-5.



Fig. S7. High-resolution XPS spectra of N 1s collected on $Co_4N-Co_3O_4$ -C/CC-1 and $Co_4N-Co_3O_4$ -C/CC-5.

The nitrogen atomic percentages of Co₄N-Co₃O₄-C/CC-1 and Co₄N-Co₃O₄-C/CC-5 are 4% and 7% according to the XPS analysis which is similar with EDX results. When the plasma treatment is prolonged to 10 min, the sample material is almost etched away from carbon cloth and the surface of carbon cloth becomes smooth again, which results in that the high-resolution XPS spectra of N 1s collected on Co₄N-Co₃O₄-C/CC-10 cannot be used to compare with those on Co₄N-Co₃O₄-C/CC-1 and Co₄N-Co₃O₄-C/CC-5. Therefore it is not shown in **Fig. S7**.



Fig. S8. The CV curves of (a) ZIF-67/CC, (b) $Co_4N-Co_3O_4$ -C/CC-1, (c) $Co_4N-Co_3O_4$ -C/CC-5, and (d) $Co_4N-Co_3O_4$ -C/CC-10 measured at different scan rates of 75, 100, 125, 150, and 175 mV s⁻¹ in KOH solution.



Fig. S9. The LSV curves of Co₄N-Co₃O₄-C/CC-5, control samples Co₄N/CC and Co₃O₄/CC.



Fig. S10. (a) The Nyquist plots of $Co_4N-Co_3O_4$ -C/CC-5, control samples Co_4N/CC and Co_3O_4/CC obtained from the EIS measurements. (b) The linear fitting of the capacitive currents of the electrodes as a function of scan rates. The CV curves of (c) Co_4N/CC and (d)

 Co_3O_4 /CC measured at different scan rates of 75, 100, 125, 150, and 175 mV s⁻¹ in KOH, respectively.



Fig. S11. XRD pattern of Co₄N-Co₃O₄-C/CC-5 after HER stability measurement for 140 h in

1.0 M KOH solution.



Fig. S12. High-resolution XPS spectra and deconvolutions of (a) Co 2p, (b) C 1s, (c) N 1s and (d) O 1s of $Co_4N-Co_3O_4$ -C/CC-5 after HER stability measurement for 140 h in 1.0 M KOH solution.



Fig. S13. (a) The LSV curve and (b) chronopotentiometry curve at 10 mA cm⁻² of AWE system.